## APJ50N65F/P/T (AP65R190)

### **650V N-Channel Enhancement Mode MOSFET**

#### Description

The APJ50N65F/P/T is CoolFET II MOSFET family

that is utilizing charge balance technology for extremely

low on-resistance and low gate charge performance.

APJ14N65F/P/T is suitable for applications which require

superior power density and outstanding efficiency

#### **General Features**

 $V_{DS} = 650V$  (Type: 740V) IDM =50A

 $R_{DS(ON)}$  < 190m $\Omega$  @  $V_{GS}$ =10V (Type: 150m $\Omega$ )

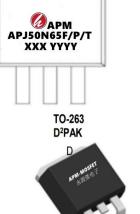


Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)







**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
APJ50N65F	TO-220F-3L	APJ50N65F XXX YYYY	1000
APJ50N65P	TO-220-3L	APJ50N65P XXX YYYY	1000
APJ50N65T	TO-263-3L	APJ50N65T XXX YYYY	1000

Absolute Maximum Ratings (T<sub>c</sub>=25 ℃ unless otherwise noted)

		<u> </u>	
Symbol	Parameter	Value	Unit
VDSS	Drain-Source Voltage (V <sub>GS</sub> = 0V)	650	V
ID	Continuous Drain Current	21	А
IDM	Pulsed Drain Current (note1)	50	Α
VGS	Gate-Source Voltage	±30	V
Eas	Single Pulse Avalanche Energy (note2)	500	mJ
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)	151	W
TJ, Tstg	Operating Junction and Storage Temperature Range	-55~+150	°C
RthJC	Thermal Resistance, Junction-to-Case	0.82	°C/W
RthJA	Thermal Resistance, Junction-to-Ambient	62	°C/W



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#### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain to source breakdown voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	650	740		V
ΔBV <sub>DSS</sub> / ΔTJ	Breakdown voltage temperature coefficient	I <sub>D</sub> =250uA, referenced to 25°C		0.7		V/°C
IDOO	Dusin to account to the man account	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V	1		1	uA
IDSS	Drain to source leakage current	v <sub>DS</sub> =520V, T <sub>C</sub> =125°C			50	uA
IGSS	Gate to source leakage current, forward	V <sub>GS</sub> =30V, V <sub>DS</sub> =0V	-		100	nA
1655	Gate to source leakage current, reverse	V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V	ı		-100	nA
VGS(TH)	Gate threshold voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	2.5	3.3	4.5	V
RDS(ON)	Drain to source on state resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =3.2A	1	150	190	mΩ
Ciss	Input capacitance		-	1510		
Coss	Output capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =100V, f=1MHz	ı	65		pF
Crss	Reverse transfer capacitance		ı	2.4		
td(on)	Turn on delay time		ı	10		
tr	Rising time	V <sub>DS</sub> =400V, I <sub>D</sub> =13A,	I	19.8		
td(off)	Turn off delay time	$R_G$ =4.7 $\Omega$ , $V_{GS}$ =13 $V$	I	45.4		ns
t <sub>f</sub>	Fall time		1	41.4		
$Q_g$	Total gate charge		ı	7.27		
Q <sub>gs</sub>	Gate-source charge	V <sub>DS</sub> =480V, V <sub>GS</sub> =10V, I <sub>D</sub> =11A	-	17.4		nC
$Q_{gd}$	Gate-drain charge			43.9		iiC
IS	Continuous source current	Integral reverse p-n Junction	-		21	Α
ISM	Pulsed source current	diode in the MOSFET			63	Α
VSD	Diode forward voltage drop.	I <sub>S</sub> =7.3A, V <sub>GS</sub> =0V		0.812	1.5	V
Trr	Reverse recovery time	Is=11A, V <sub>GS</sub> =0V, Vdd=400V,	1	288		ns
Qrr	Reverse recovery Charge	dI <sub>F</sub> /dt=100A/us,		3.66		uC

#### Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The EAS data shows Max. rating . L=0.5mH, IAS =7A, VDD =50V, RG=25 $\Omega$
- 3. The test condition is Pulse Test: ISD ≤ ID, di/dt = 100A/us, VDD≤ BVDSS, Starting at TJ =25 $^{\circ}$ C
- 4、The power dissipation is limited by 150℃ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



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### **650V N-Channel Enhancement Mode MOSFET**

### **Typical Characteristics**

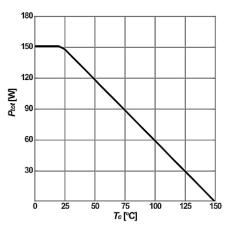


Figure1: Power dissipation (Non FullPAK)

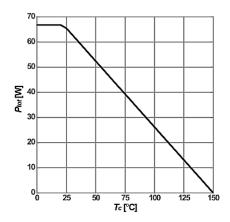


Figure3: Power dissipation  $P_{\text{tot}} = f(T_{\text{C}})$ 

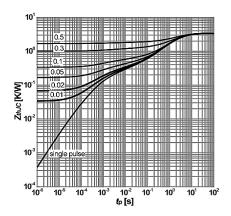


Figure5: Max. transient thermal impedance  $Z_{\text{thJC}} = f(t_p)$ ; parameter: D=  $t_p/T$ 

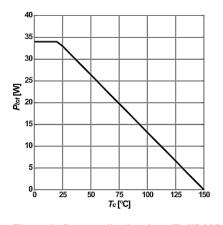


Figure2: Power dissipation (FullPAK)

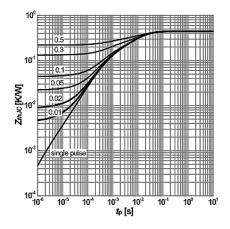


Figure4:Max. transient thermal impedance  $Z_{th,JC}$ =f( $t_p$ ); parameter: D=  $t_p$ /T

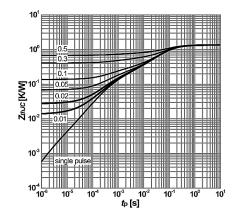


Figure 6: Max. transient thermal impedance  $Z_{thJC} = f(t_p)$ ; parameter: D=  $t_p/T$ 

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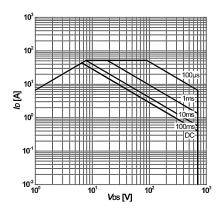


Figure 7: Safe operating area (Non FullPAK)  $I_D=f(V_{DS}); T_J=25^{\circ}C; D=0; parameter: t_P$ 

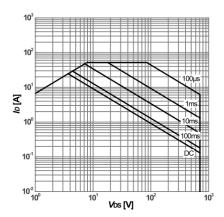


Figure9 : TSafe operating area (FullPAK-TO220A)  $R_{DS}(on)=f(I_D); T_J=25^{\circ}C;$  parameter:  $V_{GS}$ 

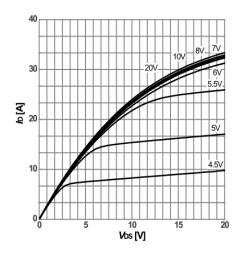


Figure 11: Typ. output characteristics

/p=f(Vps); Tj=125°C; parameter: Vps

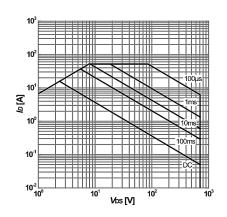


Figure8 : Safe operating area (Non FullPAK)  $I_D=f(V_{DS}); T_J=25^{\circ}C; D=0; parameter: t_p$ 

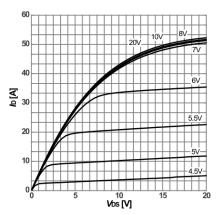


Figure 10: Typ. output characteristics  $R_{DS}(on)=f(T_j); I_D=3.2A; V_{GS}=10V$ 

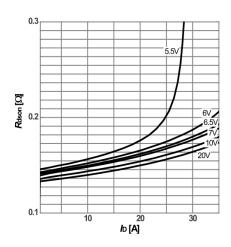
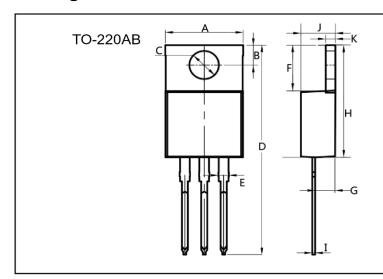


Figure 12: Type. gate charge R<sub>DS</sub>(on)=f(I<sub>D</sub>); Tj=25°C; parameter: V<sub>GS</sub>

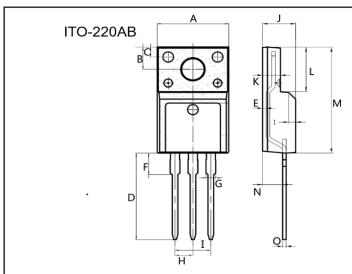


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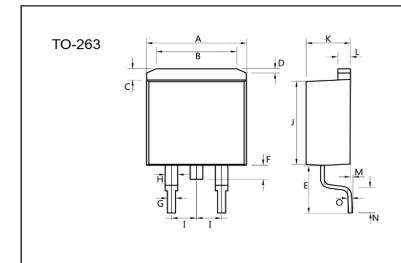
### Package Mechanical Data-TO-X



Dim.	Min.	Max.
Α	10.0	10.4
В	2.5	3.0
С	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
Н	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4
All Dimensions in millimeter		



Dim.	Min.	Max.	
Α	9.9	10.3	
В	2.9	3.5	
С	1.15	1.45	
D	12.75	13.25	
Е	0.55	0.75	
F	3.1	3.5	
G	1.25	1.45	
Н	Typ 2.54		
I	Typ 5.08		
J	4.55	4.75	
K	2.4	2. 7	
L	6.35	6.75	
М	15.0	16.0	
N	2.75	3.15	
0	0.45	0.60	
All Dimensions in millimeter			



Dim.	Min.	Max.	
Α	10.0	10. 5	
В	7.25	7.75	
С	1.3	1.5	
D	0.55	0.75	
Е	5.0	6.0	
F	1.4	1.6	
G	0.75	0.95	
Н	1.15	1.35	
I	Typ 2.54		
J	8.4	8.6	
K	4.4	4.6	
L	1.25	1.45	
М	0.02	0.1	
N	2.4	2.8	
0	0.35	0.45	
All Dimensions in millimeter			



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Edition	Date	Change
Rve1.0	2018/1/31	Initial release

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